

MOS FIELD EFFECT TRANSISTOR μ PA1811

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1811 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1811 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5- V power source
- · Low on-state resistance

RDS(on)1 = 75 m Ω MAX. (VGS = -4.5 V, ID = -2.0 A)

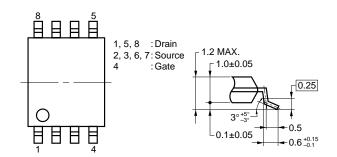
 $R_{DS(on)2} = 80 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.0 \text{ V, ID} = -2.0 \text{ A)}$

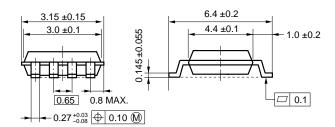
RDS(on)3 = 120 m Ω MAX. (VGS = -2.5 V, ID = -2.0 A)

ORDERING INFORMATION

| PART NUMBER | PACKAGE |
|---------------|--------------|
| μPA1811GR-9JG | Power TSSOP8 |

PACKAGE DRAWING (Unit: mm)

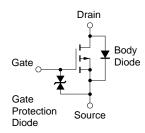




ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

| | Drain to Source Voltage | VDSS | -20 | V |
|---|-------------------------------|------------------|-------------|----|
| * | Gate to Source Voltage | Vgss | -12/+6 | V |
| | Drain Current (DC) | ID(DC) | ±4.0 | Α |
| | Drain Current (pulse) Note1 | D(pulse) | ±16 | Α |
| | Total Power Dissipation Note2 | PT | 2.0 | W |
| | Channel Temperature | Tch | 150 | °C |
| | Storage Temperature | T _{stg} | -55 to +150 | °C |

EQUIVALENT CIRCUIT



- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1 %
 - 2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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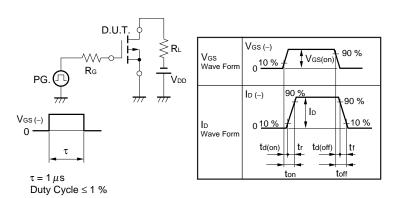
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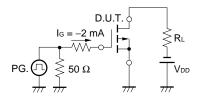
ELECTRICAL CHARACTERISTICS (TA = 25 °C)

| CHARACTERISTICS | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
|-------------------------------------|----------------------|--|------|------|------|------|
| Zero Gate Voltage Drain Current | IDSS | V _{DS} = -20 V, V _{GS} = 0 V | | | -10 | μΑ |
| Gate Leakage Current | Igss | Vgs = ±12 V, Vps = 0 V | | | ±10 | μΑ |
| Gate Cut-off Voltage | V _{GS(off)} | V _{DS} = -10 V, I _D = -1 mA | -0.5 | -0.9 | -1.5 | V |
| Forward Transfer Admittance | y _{fs} | V _{DS} = -10 V, I _D = -2.0 A | 2.5 | 6.8 | | S |
| Drain to Source On-state Resistance | RDS(on)1 | $V_{GS} = -4.5 V, I_{D} = -2.0 A$ | | 42 | 75 | mΩ |
| | RDS(on)2 | Vgs = -4.0 V, ID = -2.0 A | | 46 | 80 | mΩ |
| | RDS(on)3 | Vgs = -2.5 V, ID = -2.0 A | | 73 | 120 | mΩ |
| Input Capacitance | Ciss | V _{DS} = −10 V | | 1160 | | pF |
| Output Capacitance | Coss | V _G S = 0 V | | 680 | | pF |
| Reverse Transfer Capacitance | Crss | f = 1 MHz | | 210 | | pF |
| Turn-on Delay Time | td(on) | V _{DD} = −10 V | | 40 | | ns |
| Rise Time | tr | I _D = -2.0 A | | 100 | | ns |
| Turn-off Delay Time | td(off) | $V_{GS(on)} = -4.0 \text{ V}$ | | 90 | | ns |
| Fall Time | t _f | $R_G = 5 \Omega$ | | 60 | | ns |
| Total Gate Charge | Q _G | V _{DD} = -10 V | | 36 | | nC |
| Gate to Source Charge | Qgs | ID = -4.0 A | | 5 | | nC |
| Gate to Drain Charge | Q _{GD} | Vgs = -4.0 V | | 16 | | nC |
| Diode Forward Voltage | V _{F(S-D)} | IF = 4.0 A, VGS = 0 V | | 0.74 | | V |
| Reverse Recovery Time | trr | IF = 4.0 A, VGS = 0 V | | 77 | | ns |
| Reverse Recovery Charge | Qrr | di/dt = 100 A/μS | | 69 | _ | nC |

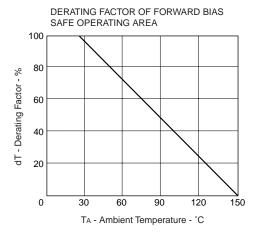
TEST CIRCUIT 1 SWITCHING TIME

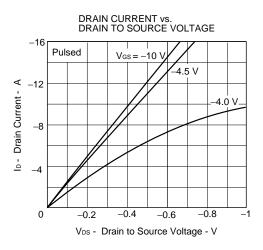


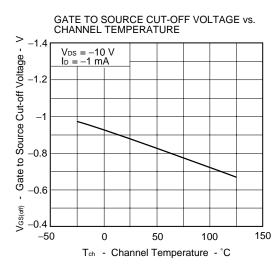
TEST CIRCUIT 2 GATE CHARGE

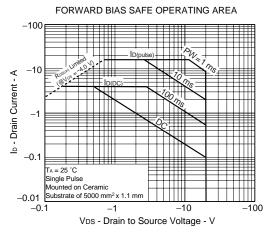


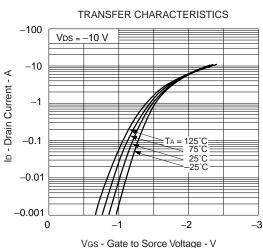
★ TYPICAL CHARACTERISTICS (T_A = 25 °C)

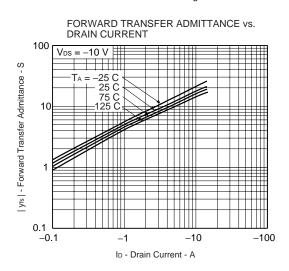


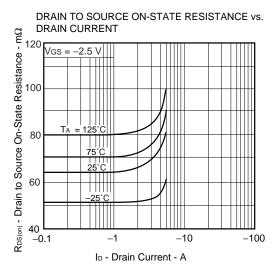


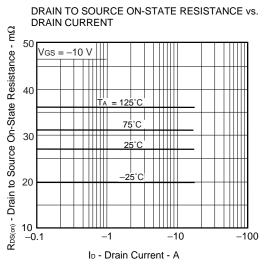


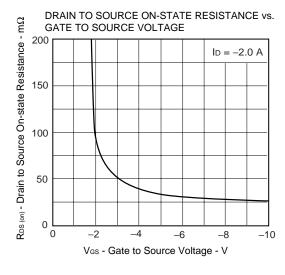


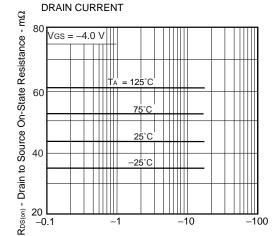












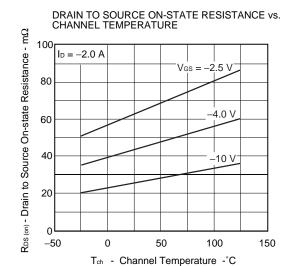
ID - Drain Current - A

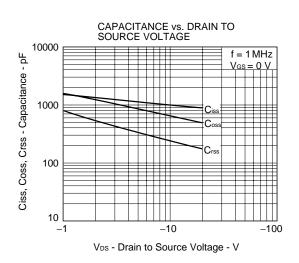
-0.1

-10

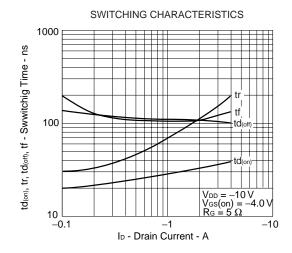
-100

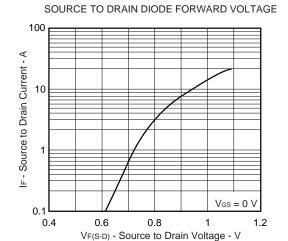
DRAIN TO SOURCE ON-STATE RESISTANCE vs.

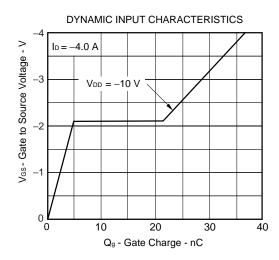




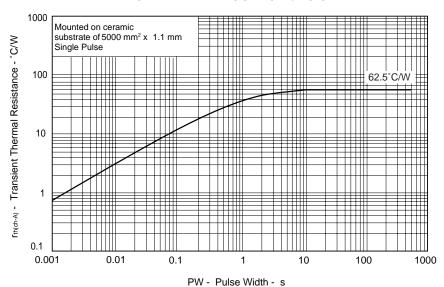
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TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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[MEMO]

NEC μ PA1811

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